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APPLICATION NO.	FI	LING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/828,773	773 04/20/2004		Badredin Fatemizadeh	112518.00005	5237
26707	7590	12/27/2005		EXAM	INER
QUARLES &	& BRAI	DY LLP	ABRAHAM, FETSUM		
RENAISSAN		RAL AVENUE		ART UNIT	PAPER NUMBER
PHOENIX A			2826	-	

DATE MAILED: 12/27/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)
	10/828,773	FATEMIZADEH ET AL.
Office Action Summary	Examiner	Art Unit
	Fetsum Abraham	2826
The MAILING DATE of this communication ap Period for Reply	pears on the cover sheet with the c	correspondence address
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING D - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statut Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).	DATE OF THIS COMMUNICATION 136(a). In no event, however, may a reply be tin will apply and will expire SIX (6) MONTHS from e, cause the application to become ABANDONE	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).
Status		
1) ☐ Responsive to communication(s) filed on 03 C 2a) ☐ This action is FINAL. 2b) ☐ This 3) ☐ Since this application is in condition for allowed closed in accordance with the practice under the condition of the co	s action is non-final. noe except for formal matters, pro	
Disposition of Claims		
4) Claim(s) 7-11,13-17,19-20-32 is/are pending i 4a) Of the above claim(s) is/are withdra 5) Claim(s) is/are allowed. 6) Claim(s) the rest is/are rejected. 7) Claim(s) 13,15,22,27 and 29-31 is/are objecte 8) Claim(s) are subject to restriction and/o Application Papers 9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) accomposite and applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examine	ed to. or election requirement. er. cepted or b) objected to by the Education of the drawing(s) be held in abeyance. See the control of the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required if the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing(s) is objected to by the education is required in the drawing in the education is required in the drawing in the education is required in the education is required in the education in	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
 12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Burea * See the attached detailed Office action for a list 	ts have been received. ts have been received in Applicationity documents have been received u (PCT Rule 17.2(a)).	on No ed in this National Stage
Attachment(s) Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:	(PTO-413) Ite atent Application (PTO-152)

Art Unit: 2826

DETAILED ACTION

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

Claims 7-11,14,16,17,19, are rejected under 35 U.S.C. 102(a) as being anticipated by Hatakeama et al (6,855,970).

As for claims 7,9,11 the patent discloses a JFET structure in figures 1 and 26 comprising a gate line (18) in contact with gate region formed within a trench formed in epitaxial layer (2) of first conductivity type (n-type), a first second conductivity type (P-type) region (12) deposed within the epitaxial layer directly under the gate, a second second conductivity type (P-type) region of less impurity concentration than the first second conductivity type (P-type) region formed under the first second conductivity type region (12).

As for claim 8, source region (3a) and drain region (1) are respectively formed above a first portion and under the epitaxial layer of the structure.

As for claim 10, the first region is a P+ type and the second region is a P- region semiconductor material.

As for claim 14, the second region (9) is positioned adjacent the first portion of the first region (12), the first portion in this pretext being the entire outer section of the first region.

As for claims 16,17,19 the first conductivity type of the prior art JFET device s ntype material and the first and second regions are P+ and P- type materials.

Page 3

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

Claims 20,23,24 are rejected under 35 U.S.C. 102(b) as being anticipated by Yilmaz et al (5,597,765).

The prior art shows a structure in the front page comprising a gate finger (20), an epitaxial region (12) of the first conductivity type and a first region of second conductivity type (14) within the epitaxial layer and partially, at least the bottom part under the gate region, the layer extending through at least half the depth of the oppositely doped epitaxial layer.

Please consider that the elements associated with gate electrode (68) also read on the claim language in that a portion of layer (14) is under the gate electrode (68) although is laterally spaced from the gate electrode and the gate finger (20) is a gate element associated with the gate (68).

As for claim 23, the structure has trench gate, the trench formed inside layer (14) in case of gate finger (20) or inside the epitaxial layer in case of gate electrode (68).

As for claim 24, the source (72) and the drain (10) are located at the claimed locations in relation to the epitaxial layer (12).

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 21,25,26 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yilmaz et al (5,597,765).

The patent discloses all subject matter claimed but may have limited the figures to a single device representing the specific invention. However, it would have been obvious to one skilled in the art to repeat the same structure in a common substrate because the front page drawing indicates the extension of the overall structure at least in the left side of the structure and since similar devices are commonly fabricated on a single wafer to save material, to reduce fabrication time and steps.

As for claim 25, the prior art may have a p-type semiconductor material but it would have bee obvious to one skilled in the art to reverse the conductivity types of the structure without compromising the inventive concept since such practice is common in the art with the most visible effects being application voltage polarity and device mobility.

As for claim 26, the first region in the prior art is a P-type material. Although the doping level of the region is not as high as the claimed region, it would have been obvious to one skilled in the art to dope such regions very high as in the claimed structures in such application provides a device with a relatively higher voltage application than devices having less doped layer for the specific region.

Art Unit: 2826

Claims 28,32 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hatakeama et al (6,855,970).

The prior art discloses all subject matter claimed including source, drain and deeply extended into an epitaxial layer first region (109) as shown in the JFET figure 12, but may have omitted the functional language on source/drain resistance reduction effect of the penetration of said first region into the epitaxial layer. However, it would have been obvious to one skilled in the art to safely assume the effect is also established by the prior art since the first region of the prior art substantially penetrates into the epitaxial layer of the JFET and since such structures allow the gate to modulate relatively larger area of the channel in JFET as of its depletion and conductance are considered which may have effect in the source/drain resistance reduction as a result.

Claim 15,13,22,27,29,30,31 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Fetsum Abraham whose telephone number is: 571-272-1911. The examiner can normally be reached on 8:00 - 18:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan J Flynn can be reached on 571-272-1915.

um Moraham